

Product Change Notification - GBNG-10TTAV974

Date:

24 Aug 2019

Product Category:

Others; Ethernet PHYs

Affected CPNs:



Notification subject:

CCB 3782 Final Notice: Qualification of MTAI as an additional assembly site for selected Micrel products of the 0.18 um wafer technology at DBHU available in 48L TQFP (7x7x1.0mm) package.

Notification text:

PCN Status:

Final notification

PCN Type:

Manufacturing Change

Microchip Parts Affected:

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:

Qualification of MTAI as an additional assembly site for selected Micrel products of the 0.18 um wafer technology at DBHU available in 48L TQFP (7x7x1.0mm) package.

Pre Change:

Assembled at ASE using CRM-1076WA die attach and G631H molding compound material.

Post Change:

Assembled at ASE using CRM-1076WA die attach and G631H molding compound material or assembled at MTAI using 3280 die attach and G700HA molding compound material.

Pre and Post Change Summary:

	Pre Change	Post C	Change
	A OF INIO	A OF INIO	Microchip
Assembly Site	ASE INC. (ASE)	ASE INC. (ASE)	Technology Thailand (HQ)
	(7102)	(7102)	(MTAI)
Wire material	Au	Au	Au
Die attach material	CRM-1076WA	CRM-1076WA	3280
Molding compound material	G631H	G631H	G700HA
Lead frame material	C7025	C7025	C7025

Impacts to Data Sheet:

None

Change Impact:

None

Reason for Change:

To improve productivity by qualifying MTAI as an additional assembly site.

Change Implementation Status:

In Progress

Estimated First Ship Date:

August 03, 2019 (date code: 1931)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and



post change parts.

Time Table Summary:

	June 2019			July 2019			August 2019								
Workweek	22	23	24	25	26	27	28	29	30	31	32	33	34	35	
Initial PCN Issue Date				X											
Qual Report Availability						X									
Final PCN Issue Date						X									
Estimated										V					
Implementation Date										^					

Method to Identify Change:

Traceability code

Qualification Report:

Please open the attachments included with this PCN labeled as PCN_#_Qual Report.

Revision History:

June 24, 2019: Issued initial notification.

July 03, 2019: Issued final notification. Attached the qualification report. Provided estimated first ship date EFSD to be on August 03, 2019.

August 24, 2019: Re-issued final notification. Revised the affected CPN list to include parts that are only assembled at ASE.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s):

PCN GBNG-10TTAV974 Qual Report.pdf

Please contact your local <u>Microchip sales office</u> with questions or concerns regarding this notification.

Terms and Conditions:

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If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

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Affected Catalog Part Numbers (CPN)

KSZ8041FTL

KSZ8041FTLI

KSZ8041FTLI-TR

KSZ8041FTL-TR

KSZ8041TL

KSZ8041TLI

KSZ8041TLI-TR

KSZ8041TL-TR

SPNY801037

SPNZ801037

SPNZ801037-TR

SPNZ801053

SPNZ801053-TR

SPNZ801087

Date: Friday, August 23, 2019



QUALIFICATION REPORT SUMMARY RELIABILITY LABORATORY

PCN #: GBNG-10TTAV974

Date May 28,2019

Qualification of MTAI as an additional assembly site for selected Micrel products of the 0.18 um wafer technology at DBHU available in 48L TQFP (7x7x1.0mm) package.



Purpose Qualification of MTAI as an additional assembly site for selected Micrel

products of the 0.18 um wafer technology at DBHU available in 48L

TQFP (7x7x1.0mm) package.

CCB No 3782

CN ES288018

QUAL ID Q19049 Rev. A

MP CODE TKDA1TCQAA02

Part No. KSZ8041TLI/TR

Bonding No. BDM-002103 Rev. A

<u>Package</u>

Type 48L TQFP

Package size 7x7x1.0 mm

Die thickness 11 mils

Die size 61.9 x 54.7 mils

Lead Frame

Paddle size 200 x 200 mils

Material C7025

Surface Ag ring plated

Process Stamp

Lead Lock No

Part Number 10104806

Treatment Roughened

<u>Material</u>

Epoxy 3280
Wire Au wire
Mold Compound G700HA
Plating Composition Matte Tin



Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code			
MTAI195200001.000	DU02919478616.B00	1913TY9			
MTAI195203365.000	DU02919478616.B00	1913DCW			
MTAI195203366.000	DU02919478616.B00	1913DCY			

Result	X Pass	Fail	

48L TQFP assembled by MTAI pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 1 at 260°C reflow temperature per IPC/JEDEC J-STD-020D standard.

PACKAGE QUALIFICATION REPORT								
Test Number (Reference)	Test Condition	Standard / Method	Qty. (Acc.)	Def/SS	Result	Remarks		
Moisture/Reflow Sensitivity Classification Test (At MSL Level 1)	85°C/ 85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243 (IPC/JEDEC J-STD-020D)	IPC/JEDE C J-STD- 020D	135	0/135	Pass			

Precondition Prior Perform	Electrical Test :+25°C and 85°C System: LTX_D1X	JESD22- A113	693(0)	693		Good Devices
Reliability Tests (At MSL Level 1)	Bake 150°C, 24 hrs System: CHINEE			693		
	85°C/85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH			693		
	3x Convection-Reflow 265°C max			693		
	System: Vitronics Soltec MR1243					
	Electrical Test :+25°C and 85°C System: LTX_D1X			0/693	Pass	

PACKAGE QUALIFICATION REPORT								
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks		
	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H	JESD22- A104		231		Parts had been pre-conditioned at 260°C		
Temp Cycle	Electrical Test: +85°C System: LTX_D1X		231(0)	0/231	Pass	77 units / lot		
	Bond Strength: Wire Pull (> 2.5 grams)		15 (0)	0/15	Pass			
	Bond Shear (>15.00 grams)		15 (0)	0/15	Pass			
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22- A118		231		Parts had been pre-conditioned at 260°C		
UNBIASED-HAS I	Electrical Test: +25°C System: LTX_D1X		231(0)	0/231	Pass	77 units / lot		
	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 3.3 Volts System: HAST 6000X	JESD22- A110		231		Parts had been pre-conditioned at 260°C		
HAST	Electrical Test:+25°C and 85°C System: LTX_D1X		231(0)	0/231	Pass	77 units / lot		

	PACKAGE QUALIFICATION REPORT								
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks			
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: SHEL LAB	JESD22- A103		45		45 units			
	Electrical Test :+25°C and 85°C System: LTX_D1X		45(0)	0/45	Pass				
Solderability	Steam Aging: Temp 93°C,8Hrs System: SAS-3000	J-STD-002	22 (0)	22					
Temp 215°C	Solder Dipping: Solder Temp.215°C			22					
	Solder material: SnPb Sn63,Pb37 System: ERSA RA 2200D Visual Inspection: External Visual Inspection			0/22	Pass				
\A/:	Wire sweep Inspection 15 Wires / lot	-	45(0)	0/45	Pass				
Wire sweep	13 Wiles / lot		Wires						
Bond Strength	Wire Pull (> 2.5 grams)	M2011	30 (0) Wires	0/30	Pass				
Data Assembly	Bond Shear (>15.00 grams)	JESD22- B116	30 (0) bonds	0/30	Pass				